

Contribution ID: 32

Type: **Oral**

Radiation Tests of Point-of-Load DC-DC Converter and Extended Common Mode LVDS Components

Tuesday 1 July 2014 14:00 (20 minutes)

In this paper the results of SEE tests on European Point-of-Load DC-DC converter and Extended Common Mode LVDS components using TFSMART2 technology will be presented.

TFSMART2 is an HV BCD technology on SOI with the smallest feature size of 0.35 μ m. During the AMICSA 2012 conference an unbiased TID radiation test of this technology using the same components has been presented.

This paper will follow-up with new results. Currently running low dose-rate biased TID test will also be presented, if finished until the conference.

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Session Classification: Applications for Radiation Hardened Analogue and Mixed-Signal ASICs

Track Classification: AMICSA 2014